

Search Notes



Application/Control No.

10/631.057

Examiner

Quoc A. Tran

**Applicant(s)/Patent under
Reexamination**

DINH ET AL.

Art Unit

2176

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
INVENTORS SEARCH CHECK FOR DOUBLE PATENT	9/28/2005	
EAST (US-PAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) see Search History Printout	9/28/2005	
NPL IEEE DataBase see Search History Printout	9/28/2005	